

A new measure for calculating multiple fault coverage of microprocessor self-test

Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.ester.ee/record=b2150914*est

New fault models and self-test generation for microprocessors using High-Level Decision Diagrams

Jasnetski, Artjom; **Raik, Jaan; Tšertov, Anton; Ubar, Raimund-Johannes** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

Software-based self-test generation for microprocessors with high-level decision diagrams

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Software-based self-test generation for microprocessors with high-level decision diagrams

Ubar, Raimund-Johannes; Tšertov, Anton; Jasnetski, Artjom; Brik, Marina LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill